



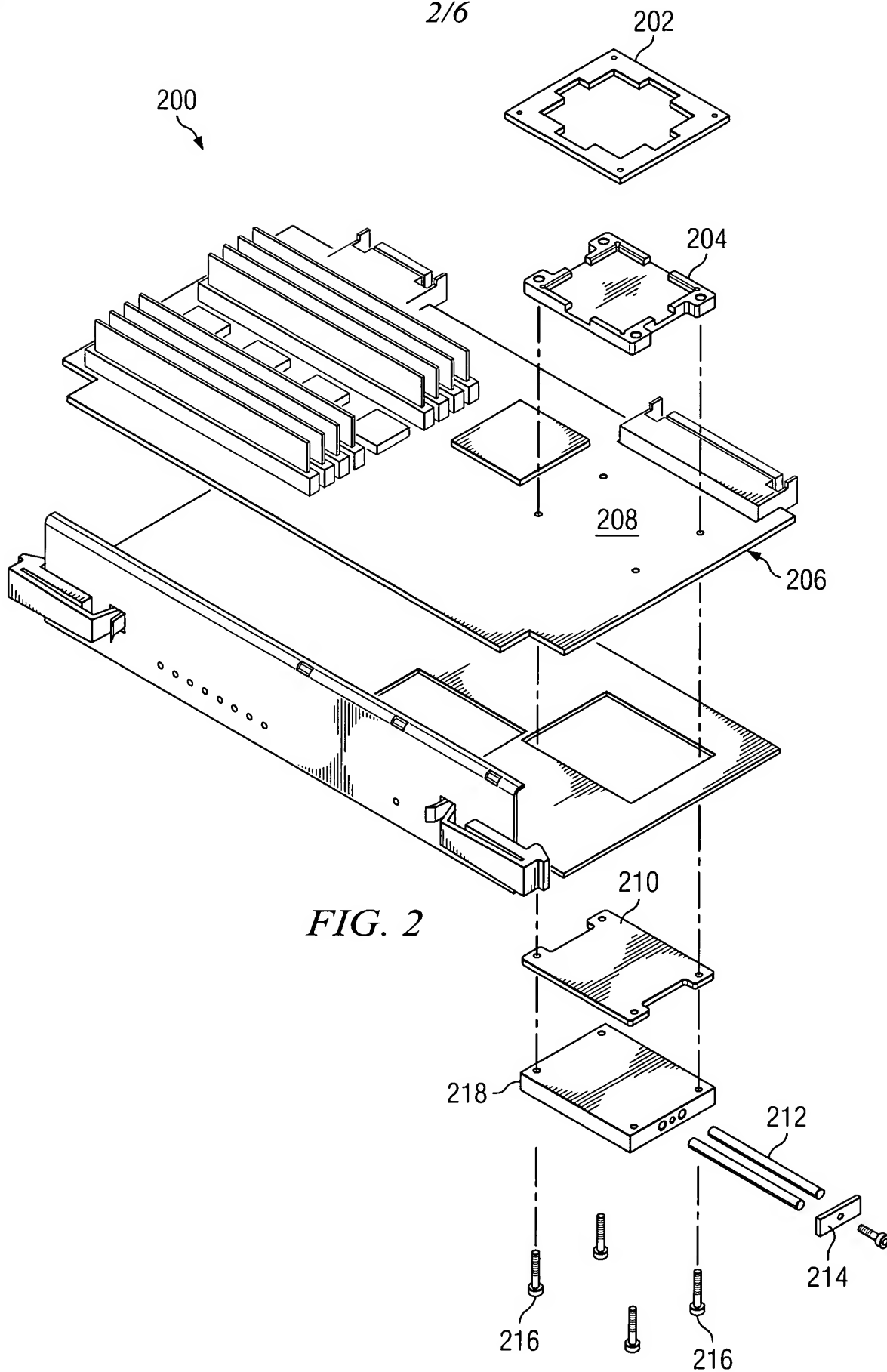
10/645,038

Cannon et al.

Apparatus For Functional and Stress Testing
of Exposed Chip Land Grid Array Devices

REPLACEMENT
SHEET

2/6



6/6

